

承 认 书

SPECIFICATION FOR APPROVAL

客户名称:
 CUSTOMER: _____
 产品名称 多层片式瓷介电容器
 PARTNAME: Multilayer Chip Ceramic Capacitor
 产品规格 0402 (COG、X7R、X5R、Y5V)


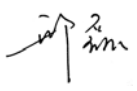
0603 (COG、X7R、X5R、Y5V)

0805 (COG、X7R、X5R、Y5V)

SPECIFICATION: 1206 (COG、X7R、X5R、Y5V)

承认书编号
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1. 电容器及介质分类 **Types of Capacitor and Dielectric Material**

※C0G: 此类介质材料的电容器为 I 类电容器, 包括常规 C0G 产品和 HQ C0G 产品。此类产品电性能稳定, 几乎不随温度、电压和时间的变化而变化。适用于低损耗, 稳定性要求高的电路中, 如滤波器、谐振器和计时电路中。

※C0G : The capacitor of this kind dielectric material is considered as Class I capacitor, including general capacitor and high frequency C0G capacitor. The electrical properties of C0G capacitor are the most stable one and have little change with temperature, voltage and time. They are suited for applications where low-losses and high-stability are required, such as filters, oscillators, and timing circuits.

※X7R、X5R: 此类介质材料的电容器为 II 类电容器, 具有较高的介电常数, 容量比 I 类电容器高, 具有较稳定的温度特性, 适用于容量范围广, 稳定性要求不高的电路中, 如隔直、耦合、旁路、鉴频等电路中。

※ X7R、X5R: X7R、X5R material is a kind of material has high dielectric constant. The capacitor made of this kind material is considered as Class II capacitor whose capacitance is higher than that of class I. These capacitors are classified as having a semi-stable temperature characteristic and used over a wide temperature range, such in these kinds of circuits, DC-blocking, decoupling, bypassing, frequency discriminating etc.

※Y5V: 此类介质材料的电容器为 II 类电容器, 是所有电容器中介电常数最大的电容器, 但其容量稳定性较差, 对温度、电压等条件较敏感, 适用于要求大容量, 温度变化不大的电路中。

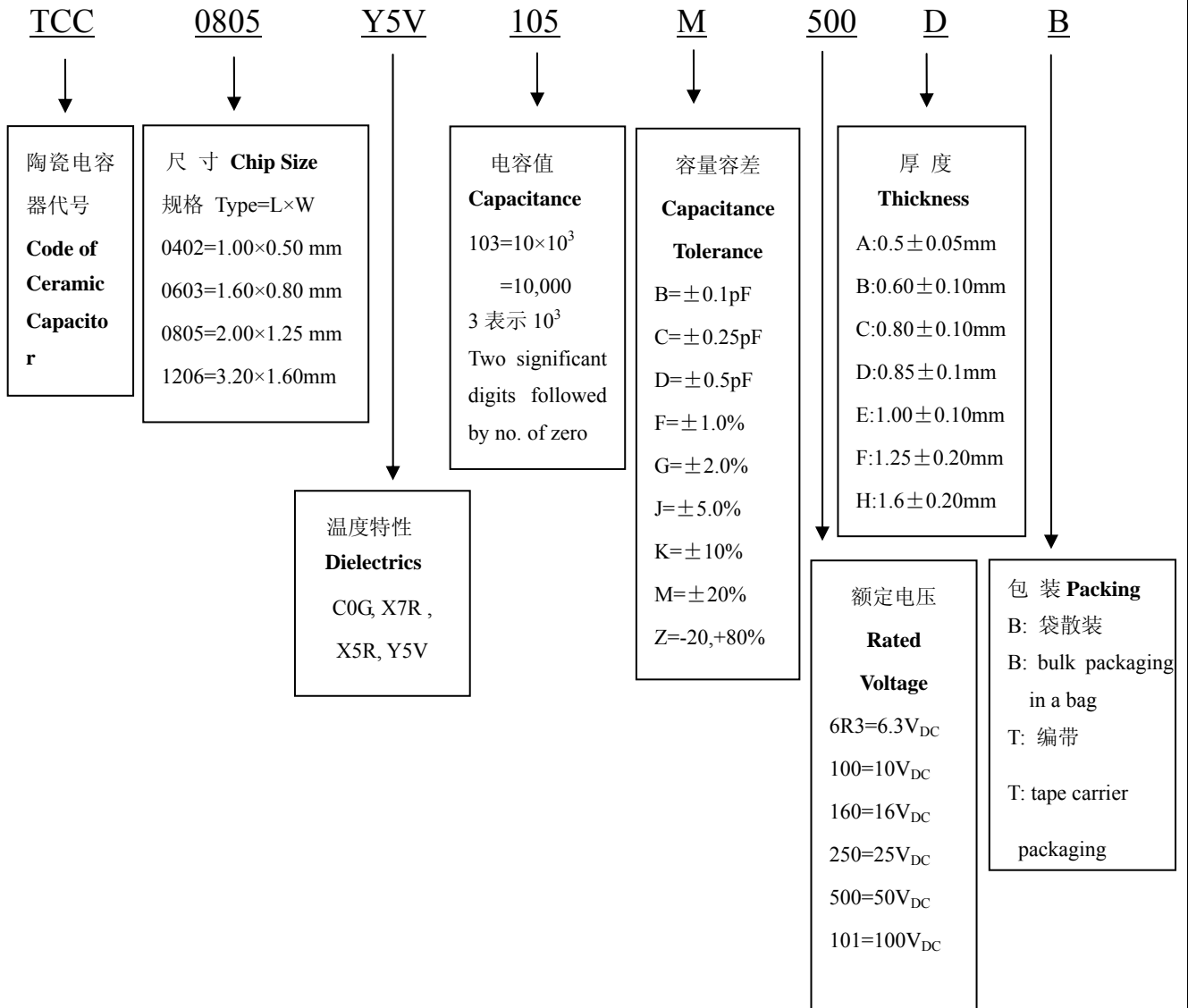
※Y5V: The capacitor made of this kind of material is the highest dielectric constant of all ceramic capacitors. They are used over a moderate temperature range in application where high capacitance is required because of its unstable temperature coefficient, but where moderate losses and capacitance changes can be tolerated. Its capacitance and dissipation factors are sensible to measuring conditions, such as temperature and voltage, etc

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2. 常规产品命名

General Product Parts Numbering System

(例) (example)



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3. 常规产品容量范围 General Product Capacitance Range

表 1 Table 1

		常规 COG(General COG)											
Cp	V _{DC}	0402			0603			0805			1206		
		50	25	16	50	25	16	50	25	16	50	25	16
0R2		A			C			B			B		
0R5		A			C			B			B		
1R0		A			C			B			B		
2R0		A			C			B			B		
3R0		A			C			B			B		
4R0		A			C			B			B		
5R0		A			C			B			B		
6R0		A			C			B			B		
7R0		A			C			B			B		
8R0		A			C			B			B		
9R0		A			C			B			B		
100		A			C			B			B		
120		A			C			B			B		
150		A			C			B			B		
180		A			C			B			B		
200		A			C			B			B		
220		A			C			B			B		
270		A			C			B			B		
300		A			C			B			B		
330		A			C			B			B		
390		A			C			B			B		
470		A			C			B			B		
560		A			C			B			B		
680		A			C			B			B		
820		A			C			B			B		
101		A			C			B			B		
121		A			C			B			B		
151		A	A		C			B			B		
181		A	A		C			B			B		
201		A	A		C			B			B		
221		A	A		C			B			B		
271		A	A		C			B/D			B/D		
331		A	A		C			B/D			B/D		
391			A		C			B/D			B/D		
471			A		C	C		B/D			B/D		
561					C	C		B/D			B/D		
681					C	C		B/D			B/D		
821					C	C		B/D			B/D		
102					C	C		B/D			B/D		
152					C	C		B/D			B/D		
182						C		B/D/E			B/D		
222						C		D/E/F	D/E/F		B/D		

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332									D/E/F		B/D/E	B/D/E	
472									D/E/F		B/D/E	B/D/E	
562									D/E/F			B/D/E	
103										D/E/F		D/E/F	D/E/F

容量容差: C0G(0.2pF~4.9pF): B/C; C0G(5.0pF~9.9pF): D;
 C0G(≥ 10 pF): F($\pm 1\%$), G($\pm 2\%$), J($\pm 5\%$), K($\pm 10\%$)
 厚度: A:0.50 \pm 0.05mm B:0.60 \pm 0.10mm C:0.80 \pm 0.10mm D:0.85 \pm 0.10mm
 E:1.00 \pm 0.10mm F:1.25 \pm 0.20mm H:1.60 \pm 0.20mm
 以上容量仅供参考, 具体容量取决于使用要求。
 Tolerance: C0G(0.2pF~4.9pF): C C0G(5.0pF~9.9pF): D
 C0G(≥ 10 pF): F($\pm 1\%$), G($\pm 2\%$), J($\pm 5\%$)
 Thickness: A:0.50 \pm 0.10mm B:0.60 \pm 0.10mm C:0.80 \pm 0.10mm D:0.85 \pm 0.10mm
 E:1.00 \pm 0.10mm F:1.25 \pm 0.20mm H:1.60 \pm 0.20mm
 Above capacitance for reference only, actual cap. Range depends on the standard products.

表 2 Table 2

X7R/X5R																				
Cp V _{DC}	0402					0603					0805					1206				
	50	25	16	10	6.3	50	25	16	10	6.3	50	25	16	10	6.3	50	25	16	10	6.3
101	A					C					B/D					B/D				
151	A					C					B/D					B/D				
181	A					C					B/D					B/D				
221	A					C					B/D					B/D				
271	A					C					B/D					B/D				
331	A					C					B/D					B/D				
391	A					C					B/D					B/D				
471	A					C					B/D					B/D				
561	A					C					B/D					B/D				
681	A					C					B/D					B/D				
102	A					C					B D					B/D				
122	A					C					B/D					B/D				
152	A					C					B/D					B/D				
182	A					C					D					B/D				
222	A					C					D					B/D				
272	A					C					D					B/D				
332	A					C					D					B/D				
392	A					C					D					B/D				
472	A					C					D					D				
562	A	A				C					D					D				
682	A	A				C					D					D				
103	A	A	A			C					D					D				
153		A	A			C					D					D				
183		A	A			C					D					D				
223		A	A	A		C					D					D				
273		A	A	A		C					D					D				
333		A	A	A		C					D					D				
393		A	A	A		C					D					D				

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473		A	A	A		C					D					D			
563			A	A		C	C				D					D			
683			A	A		C	C				D					D			
104			A	A		C	C				D	D				D	D		
154				A			C	C			D/E/F	D				D/E	D/E		
184				A			C	C			D/E/F	D				D/E	D/E		
224				A	A		C	C			D/E/F	D/E				D/E	D/E		
274					A			C				D/E/F				D/E/F	D/E/F		
334					A			C				D/E/F				D/E/F	D/E/F		
474					A			C	C			D/E/F	D/E/F			D/E/F	D/E/F	D/E/F	
684					A			C	C			D/E/F	D/E/F				E/F	E/F	
105					A			C	C			D/E/F	D/E/F	D/E/F			E/F/H	E/F/H	E/F/H
225									C	C				F	F			F/H	F/H
475										C					F			F/H	F/H
106														F	F			F/H	F/H
226															F				F/H

容量容差: X7R/X5R: J(±5.0%); K(±10%); M(±20%)

厚度: A:0.50±0.05mm B:0.60±0.10mm C:0.80±0.10mm D:0.85±0.10mm

E:1.00±0.10mm F:1.25±0.20mm H:1.60±0.20mm

以上容量仅供参考, 具体容量取决于使用要求。

Tolerance: X7R/X5R: J(±5.0%),K(±10%),M(±20%)

Thickness: A:0.50±0.10mm B:0.60±0.10mm C:0.80±0.10mm D:0.85±0.10mm

E:1.00±0.10mm F:1.25±0.20mm H:1.60±0.20mm

Above capacitance for reference only, actual cap. range depends on the standard products.

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表3 Table 3

Y5V																				
Cp V _{DC}	0402					0603					0805					1206				
	50	25	16	10	6.3	50	25	16	10	6.3	50	25	16	10	6.3	50	25	16	10	6.3
102	A																			
152	A																			
222	A					C														
332	A					C														
472	A					C														
683	A					C														
103	A					C					B					B/D				
153	A	A				C					B					B/D				
223	A	A				C					B					B/D				
333	A	A	A			C					B/D					B/D				
473	A	A	A			C					B/D					B/D				
683		A	A			C	C				B/D					B/D				
104		A	A	A		C	C				B/D					B/D				
154			A	A		C	C				B/D					B/D				
224			A	A		C	C	C			B/D	B/D				B/D	B/D			
334				A		C	C	C			D/E/F	D/E/F				D/E	D/E			
474				A		C	C	C			D/E/F	D/E/F	D/E/F			D/E	D/E	D/E		
684					A		C	C	C		D/E/F	D/E/F	D/E/F			D/E	D/E	D/E		
105					A		C	C	C		D/E/F	D/E/F	D/E/F			D/E	D/E	D/E		
155									C			E/F	E/F	E/F			D/E	D/E		
225									C			E/F	E/F	E/F			E/F	E/F		
335										C			E/F	E/F			E/F	E/F	E/F	
475										C			E/F	E/F	E/F			F/H	F/H	
106														E/F	E/F			F/H	F/H	
226															E/F				F/H	F/H

容量容差: Y5V: M($\pm 20\%$); Z(-20,+80%)

厚度: A:0.50 \pm 0.05mm B:0.60 \pm 0.10mm C:0.80 \pm 0.10mm D:0.85 \pm 0.10mm
 E:1.0 \pm 0.10mm F:1.25 \pm 0.20mm H:1.60 \pm 0.20mm

以上容量仅供参考, 具体容量取决于使用要求。

Tolerance: Y5V: M($\pm 20\%$),Z(-20,+80%)

Thickness: A:0.05 \pm 0.10mm B:0.60 \pm 0.10mm C:0.80 \pm 0.10mm D:0.85 \pm 0.10mm
 E:1.00 \pm 0.10mm F:1.25 \pm 0.20mm H:1.60 \pm 0.20mm

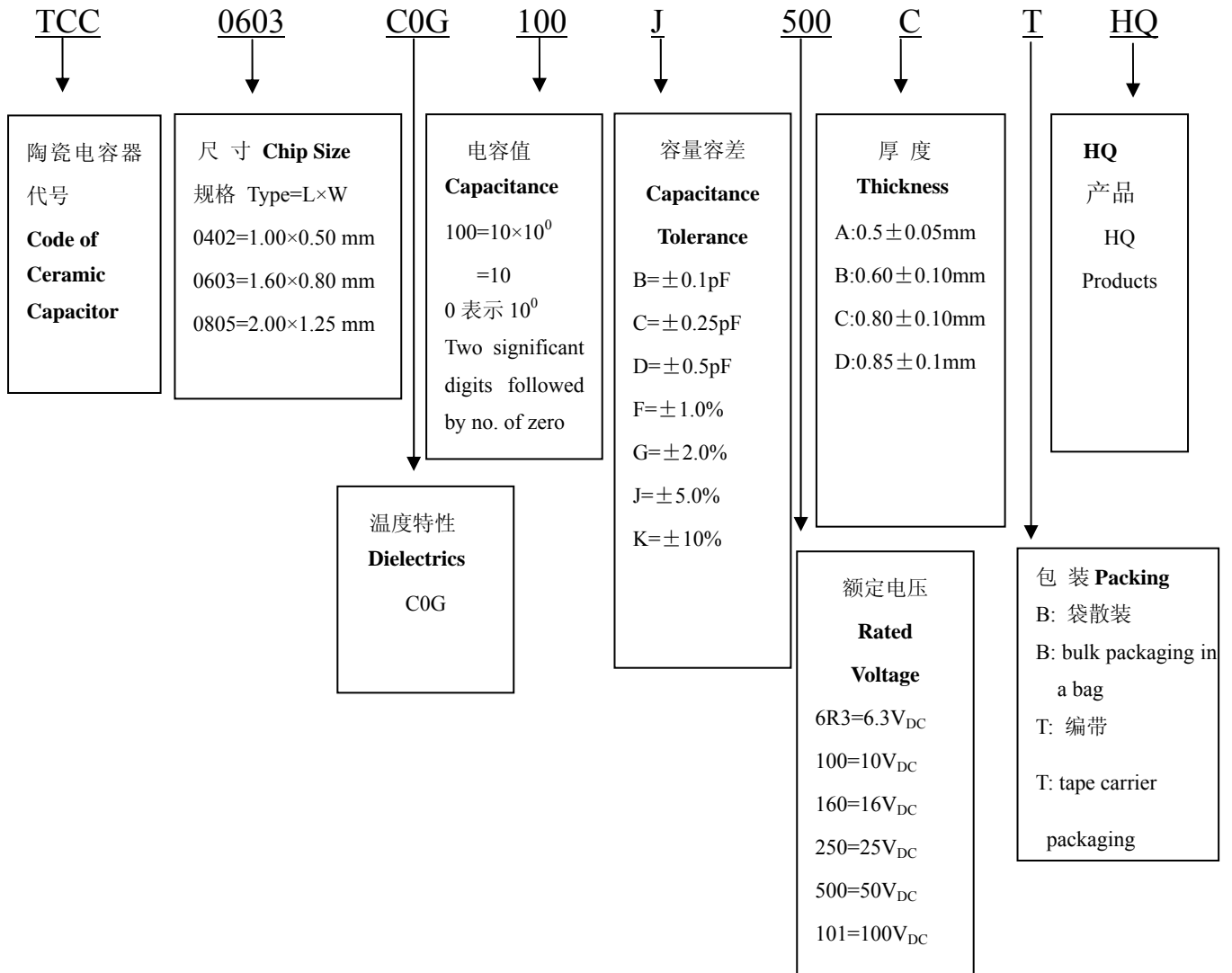
Above capacitance for reference only, actual cap. range depends on the standard products.

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4. 高频 C0G 产品型号命名

HQ C0G Product Parts Numbering System

(例) (example)



与常规 C0G 相比，高频 C0G 具有更高 Q 值以及低 ESR，适用于射频 RF 电路及要求 Hi-Q、低 ESR、高频率响应的微波电路中。

Comparing with general C0G capacitor, HQ C0G capacitor take on higher Q-value and lower ESR, are ideally suited for RF and microwave application requiring high Q, low ESR, and high resonant frequency.

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5. 高频 COG 容量范围 HQ COG Product Capacitance Range

表 1 Table 1

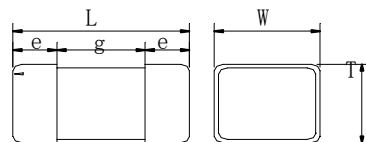
		高频 COG(HQ COG)								
		0402			0603			0805		
Cp	V _{DC}	50	25	16	50	25	16	50	25	16
0R2		A			C			B		
0R5		A			C			B		
1R0		A			C			B		
2R0		A			C			B		
3R0		A			C			B		
4R0		A			C			B		
5R0		A			C			B		
6R0		A			C			B		
7R0		A			C			B		
8R0		A			C			B		
9R0		A			C			B		
100		A			C			B		
120		A			C			B		
150		A			C			B		
180		A			C			B		
200					C			B		
220					C			B		
270					C			B		
300					C			B		
330					C			B		
390					C			B		
470					C			B		
560					C			B		
680					C			B/D		
820					C			B/D		
101					C			B/D		

使用频率在 1MHz~1GHz 之间； Frequency is between 1MHz and 1GHz

6. 产品尺寸 Dimensions

规格：0402、0603、0805、1206

Chip Size: 0402, 0603, 0805 and 1206



规格 Type	L (mm)	W (mm)	e (mm)	g min (mm)	T (mm)				
0402	1.0±0.05	0.5±0.05	0.15~0.3	0.4	0.50±0.05	—	—	—	—
0603	1.6±0.1	0.8±0.1	0.2~0.5	0.5	0.80±0.10	—	—	—	—
0805	2.0±0.1	1.25±0.1	0.2~0.7	0.7	0.60±0.10	0.85±0.10	1.00±0.10	1.25±0.20	—
1206	3.2±0.1	1.60±0.1	0.3~0.8	1.6	0.60±0.10	0.85±0.10	1.00±0.10	1.25±0.20	1.60±0.20

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7. 技术要求和测试条件 **Specification and Test Condition**

7.1 外观 Appearance

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G/X7R/X5R/Y5V	无损伤或异常 No defects or abnormalities	目视检查 Visual inspection.

7.2 尺寸 Dimensions

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G/X7R/X5R/Y5V	在要求的范围内 Within the specified dimensions	用千分尺 Using calipers on micrometer

7.3 容量 Capacitance

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	在要求的容值容差范围内 Within the specified tolerance B:±0.1pF;C:±0.25pF;D:±0.5pF;J: ±5%	1.0±0.2Vrms, 1MHz±10% (C>1000 pF, 1.0±0.2Vrms, 1KHz±10%,) 25℃。
X7R/X5R	在要求的容值容差范围内 Within the specified tolerance J: ±5%; K: ±10%; M: ±20%	1.0±0.2Vrms, 1KHz±10% (Cp> 10uF,0.5±0.1Vrms,120±24Hz) 25℃,预处理后 48hrs。 at 25℃,48hrs after annealing
Y5V	在要求的容值容差范围内 Within the specified tolerance M: ±20%; Z: -20%, +80%	1.0±0.2Vrms, 1KHz±10% (Cp> 10uF,0.5±0.1Vrms,120±24Hz) 25℃, 预处理后 48hrs。 at 25℃, 48hrs after annealing

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7.4 损耗 Dissipation Factor

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	$C_p < 30\text{pF}$, $Q \geq 400 + 20C_p$; $C_p \geq 30\text{pF}$, $Q \geq 1000$	$1.0 \pm 0.2V_{rms}$, $1\text{MHz} \pm 10\%$, 25°C ($C_p > 1000\text{pF}$, $1.0 \pm 0.2V_{rms}$, $1\text{KHz} \pm 10\%$)
X7R	$U_R \geq 25\text{V}$, $DF \leq 3.5\%$ $DF \leq 5.0\%$ (0402 $\geq 0.033 \mu\text{F}$, 0603 $\geq 0.15 \mu\text{F}$, 0805 $\geq 0.68 \mu\text{F}$, 1206 $\geq 2.2 \mu\text{F}$, 1210 $\geq 6.8 \mu\text{F}$) $U_R \leq 16\text{V}$, $DF \leq 5.0\%$ $DF \leq 7.0\%$ (0402 $\geq 0.056 \mu\text{F}$, 0603 $\geq 0.56 \mu\text{F}$, 0805 $\geq 1 \mu\text{F}$, 1206 $\geq 4.7 \mu\text{F}$, 1210 $\geq 10 \mu\text{F}$) $U_R = 6.3\text{V}$, $DF \leq 7.0\%$ $DF \leq 10.0\%$ (0402 $\geq 0.33 \mu\text{F}$, 0603 $\geq 1 \mu\text{F}$, 0805 $\geq 10 \mu\text{F}$, 1206 $\geq 22 \mu\text{F}$, 1210 $\geq 47 \mu\text{F}$)	$1.0 \pm 0.2V_{rms}$, $1\text{KHz} \pm 10\%$, ($C_p > 10\mu\text{F}$, $0.5 \pm 0.1V_{rms}$, $120 \pm 24\text{Hz}$) 25°C , 预处理后 48hrs。 at 25°C , 48hrs after annealing
X5R	$U_R \geq 25\text{V}$, $DF \leq 5.0\%$ $U_R = 16\text{V}$, $DF \leq 6.0\%$ $U_R \leq 10\text{V}$, $DF \leq 7.0\%$	
Y5V	$U_R \geq 50\text{V}$, $DF \leq 7.0\%$ $U_R = 25\text{V}$, $DF \leq 7.0\%$ (0402 $\geq 0.047 \mu\text{F}$, 0603 $\geq 0.1 \mu\text{F}$, 0805 $\geq 0.33 \mu\text{F}$, 1206 $\geq 0.68 \mu\text{F}$, 1210 $\geq 1 \mu\text{F}$) $DF \leq 9.0\%$ (0402 $\geq 0.068 \mu\text{F}$, 0603 $\geq 0.47 \mu\text{F}$, 0805 $\geq 1 \mu\text{F}$, 1206 $\geq 4.7 \mu\text{F}$, 1210 $\geq 10 \mu\text{F}$) $U_R = 16\text{V}$, $DF \leq 9.0\%$ $U_R = 10\text{V}$, $DF \leq 12.5\%$ $U_R = 6.3\text{V}$, $DF \leq 15.0\%$	$1.0 \pm 0.2V_{rms}$, $1\text{KHz} \pm 10\%$, ($C_p > 10\mu\text{F}$, $0.5 \pm 0.1V_{rms}$, $120 \pm 24\text{Hz}$) 25°C , 预处理后 48hrs。 at 25°C , 48hrs after annealing

7.5 绝缘电阻 Insulation Resistance

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G/X7R/ X5R/Y5V	大于 $10\text{G}\Omega$ 或 $500\Omega \cdot \text{F}$ (大于其中较小的数值) More than $10\text{G}\Omega$ or $500\Omega \cdot \text{F}$, whichever is smaller.	25°C , 额定电压 60 ± 5 秒测量 Rated voltage for $60 \pm 5\text{sec}$, at 25°C

7.6 耐电压 Dielectric Strength

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G/X7R/X5R/Y5V	无损坏或异常 No defects or abnormalities.	当在电容器的两端施加 300% (C0G); 250% (X7R/X5R/Y5V) 的额定电压, 持续 1 至 5 秒钟, 充放电电流不超过 50mA Failure shall be observed when 300% (C0G); 250% (X7R/ X5R/Y5V) of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge /discharge current is less than 50mA

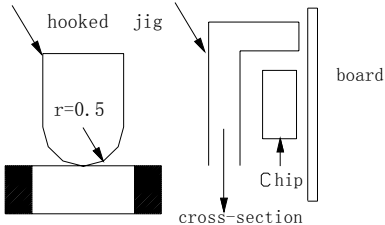
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7.7 静电容量温度特性 Temperature Coefficient of Capacitance

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition																												
C0G	容量变化在±30ppm/°C以内 容量漂移在±0.2% 或±0.05p F 以内 Temperature coefficient within ±30ppm/°C Cp drift within ±0.2% or ±0.05pF	按系列温度顺序测试电容容量 Measure capacitance under follow table list temperature: <table border="1" style="margin-left: 20px;"> <tr> <td>步骤</td> <td>C0G, X7R</td> <td>X5R</td> <td>Y5V</td> </tr> <tr> <td>STEP</td> <td></td> <td></td> <td></td> </tr> <tr> <td>1</td> <td>25 ±2</td> <td>25 ±2</td> <td>25 ±2</td> </tr> <tr> <td>2</td> <td>-55±3</td> <td>-55±3</td> <td>-30±3</td> </tr> <tr> <td>3</td> <td>25 ±2</td> <td>25 ±2</td> <td>25 ±2</td> </tr> <tr> <td>4</td> <td>125±3</td> <td>85±3</td> <td>85±3</td> </tr> <tr> <td>5</td> <td>25 ±2</td> <td>25 ±2</td> <td>25 ±2</td> </tr> </table>	步骤	C0G, X7R	X5R	Y5V	STEP				1	25 ±2	25 ±2	25 ±2	2	-55±3	-55±3	-30±3	3	25 ±2	25 ±2	25 ±2	4	125±3	85±3	85±3	5	25 ±2	25 ±2	25 ±2
步骤	C0G, X7R	X5R	Y5V																											
STEP																														
1	25 ±2	25 ±2	25 ±2																											
2	-55±3	-55±3	-30±3																											
3	25 ±2	25 ±2	25 ±2																											
4	125±3	85±3	85±3																											
5	25 ±2	25 ±2	25 ±2																											
X7R/X5R	容量变化在 ±15% 以内 Capacitance change within ±15%																													
Y5V	容量变化在 +22%, -82% 以内 Capacitance change within +22%, -82%	<p>1) C0G 容量漂移的计算方法为：用步骤 3 测量的电容容值量除以在第 1、3 和 5 步骤测量得到的误差的最大值和最小值的差。 温度系数的计算以第 3 步骤测量电容容量为参考。 The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the step 1,3 and 5. The temperature coefficient is determined using the Capacitance measured in step 3 as a reference.</p> <p>2) X7R、X5R 和 Y5V X7R ,X5R and Y5V 与 25°C 时的电容容量相比较，电容容量在温度范围内的变化在要求的范围之内。 The ranges of capacitance change compared within the above 25 °C value over the temperature ranges shall be within the specified ranges.</p>																												

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7.8 附着力 Adhesion

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G X7R/X5R Y5V	端电极无松动，也无其它不良现象 No removal of the terminations or other defect shall occur.	施加 6N(=600g*f)的压力，并保持 10±1 秒 The pressurizing force shall be 6N (=600g*f) and the duration of application shall be 10±1sec. 

7.9 可焊性 Solderability of Termination

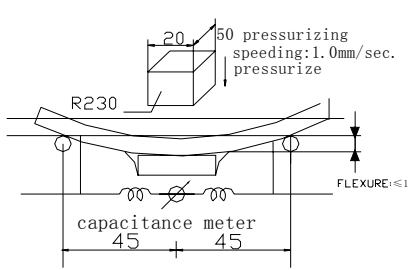
类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G X7R/X5R Y5V	端电极挂锡面积不小于 95%，针孔或粗糙面积小于 5% 95% min. coverage of both terminal electrodes and less than 5% have pin holes or rough spots.	锡炉温度：245±5℃ 浸入时间：2±1 秒 两侧端电极完全浸入焊锡炉 Solder temperature: 245±5℃ Dipping time: 2±1 seconds. Completely soak both terminal electrodes in solder

7.10 耐焊性 Resistance to leaching

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G X7R/X5R Y5V	端电极挂锡面积不小于 95%，针孔或粗糙面积小于 5%，外观无开裂 95% min. coverage of both terminal electrodes and less than 5% have pin holes or rough spots. No remarkable visual damage.	锡炉温度：270±5℃ 浸入时间：10±1 秒 两侧端电极完全浸入焊锡炉 Solder temperature: 270±5℃ Dipping time: 10±1 seconds. Completely soak both terminal electrodes in solder

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7.11 端电极结合强度 Bending

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	无可见损伤; 容量变化小于等于±5% 或 0.5 PF No remarkable visual damage Cp change ≤ ±5% or ≤ 0.5 pF	将片状电容器安装在测试夹具上,按图所示方向以 1.0mm/s 的速率施加压力,弯曲 1mm。 Solder the capacitor on testing substrate and put it on testing stand. The middle part of substrate shall successively be pressurized by pressuring rod at a rated of about 1.0mm/sec. Until the deflection become means of the 
X7R/X5R	无可见损伤; 容量变化小于等于±12.5% No remarkable visual damage Cp change ≤ ±12.5%	
Y5V	无可见损伤; 容量变化小于等于 ±30% No remarkable visual damage Cp change ≤ ±30%	

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7.12 耐焊接热 Resistance to Soldering Heat

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	无明显可见损伤 容量变化在 $\pm 2.5\%$ 或 $\pm 0.25\text{pF}$ (取较大值) 以内 DF 满足产品初始值的要求 IR 满足产品初始值的要求 No remarkable visual damage Cp change within $\pm 2.5\%$ or $\pm 0.25\text{pF}$, whichever is larger. DF meets initial standard value. IR meets initial standard value.	焊接温度: $270\pm 5^\circ\text{C}$ 预热: $120\sim 150^\circ\text{C}$ 60 秒 浸入时间: 10 ± 1 秒 在室温下放置 24 ± 2 (C0G) 或 48 ± 4 (X7R、X5R、Y5V) 小时以后测量 试验后在标准条件下恢复 *高介电常数电容器的初始值测量 在 $140\sim 150^\circ\text{C}$ 进行 1 小时的热处理后在室温下放置 48 ± 4 小时 测量初始值
X7R/X5R	无明显可见损伤 容量变化在 $\pm 5\%$ 以内 DF 满足产品初始值的要求 IR 满足产品初始值的要求 No remarkable visual damage Cp change within $\pm 5\%$ DF meets initial standard value. IR meets initial standard value.	Soldering temperature: $270\pm 5^\circ\text{C}$ Preheating: $120\sim 150^\circ\text{C}$ 60sec. Dipping time: 10 ± 1 seconds. Measurement to be made after being kept at room temperature for 24 ± 2 (C0G) or 48 ± 4 (X7R, X5R, Y5V) hours. Recov ery for the following period under the standard condition after test.
Y5V	无明显可见损伤 容量变化在 $\pm 20\%$ 以内 DF 满足产品初始值的要求 IR 满足产品初始值的要求 No remarkable visual damage Cp change within $\pm 20\%$ DF meets initial standard value. IR meets initial standard value.	*Initial measurement for high dielectric constant type Perform a heat treatment at $140\sim 150^\circ\text{C}$ for 1hr and let sit for 48 ± 4 hrs at room temperature. Perform the initial measurement.

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7.13 温度快速循环 Temperature Cycle

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition																		
C0G	无明显可见损伤 容量变化在 $\pm 2.5\%$ 或 $\pm 0.25\text{pF}$ (取较大值) 以内 No remarkable visual damage Cp change within $\pm 2.5\%$ or $\pm 0.25\text{pF}$, whichever is larger.	按下列步骤进行 5 次循环: To perform 5 cycles of the stated environment <table border="0"> <tr> <td style="text-align: right;">步骤</td> <td style="text-align: right;">温度</td> <td style="text-align: right;">时间</td> </tr> <tr> <td style="text-align: right;">Step</td> <td style="text-align: right;">Temperature</td> <td style="text-align: right;">Time</td> </tr> <tr> <td style="text-align: right;">1</td> <td style="text-align: right;">下限类别温度 $+0/-3^\circ\text{C}$ Min. operating Temp.$+0/-3^\circ\text{C}$</td> <td style="text-align: right;">30min</td> </tr> <tr> <td style="text-align: right;">2</td> <td style="text-align: right;">25°C</td> <td style="text-align: right;">2~3 min</td> </tr> <tr> <td style="text-align: right;">3</td> <td style="text-align: right;">下限类别温度 $+0/-3^\circ\text{C}$ Max. operating Temp.$+0/-3^\circ\text{C}$</td> <td style="text-align: right;">30 min</td> </tr> <tr> <td style="text-align: right;">4</td> <td style="text-align: right;">25°C</td> <td style="text-align: right;">2~3 min</td> </tr> </table>	步骤	温度	时间	Step	Temperature	Time	1	下限类别温度 $+0/-3^\circ\text{C}$ Min. operating Temp. $+0/-3^\circ\text{C}$	30min	2	25°C	2~3 min	3	下限类别温度 $+0/-3^\circ\text{C}$ Max. operating Temp. $+0/-3^\circ\text{C}$	30 min	4	25°C	2~3 min
步骤	温度	时间																		
Step	Temperature	Time																		
1	下限类别温度 $+0/-3^\circ\text{C}$ Min. operating Temp. $+0/-3^\circ\text{C}$	30min																		
2	25°C	2~3 min																		
3	下限类别温度 $+0/-3^\circ\text{C}$ Max. operating Temp. $+0/-3^\circ\text{C}$	30 min																		
4	25°C	2~3 min																		
X7R/X5R	无明显可见损伤 容量变化在 $\pm 7.5\%$ 以内 No remarkable visual damage Cp change within $\pm 7.5\%$	在室温下放置 24 ± 2 (C0G) 或 48 ± 4 (X7R、X5R、Y5V) 小时以后 测量 *高介电常数电容器的初始值测量 在 $140\sim 150^\circ\text{C}$ 进行 1 小时的热处理后在室温下放置 48 ± 4 小时 测量初始值 Measurement to be made after being kept at room temperature for $24\pm 2\text{hrs}$ (C0G) or $48\pm 4\text{hrs}$ (X7R, X5R, Y5V) at room temperature, then measure. *Initial measurement for high dielectric constant type Perform a heat treatment at $140\sim 150^\circ\text{C}$ for 1hr and let sit for $48\pm 4\text{hrs}$ at room temperature. Perform the initial measurement.																		

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7.14 稳态湿热 Moisture Resistance ,steady state

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	外观无明显可见损伤 容量变化在±5%或 ±0.5pF (取较大值) 以内 $C_p < 10\text{pF}$, $Q \geq 200 + 10C_p$; $10 \leq C_p < 30\text{pF}$, $Q \geq 275 + 2.5C_p$ $C_p \geq 30\text{pF}$, $Q \geq 350$ IR: 大于 $1000\text{M}\Omega$ 或 $50\Omega \cdot \text{F}$ (取较小值) No remarkable visual damage Cp change within ±5% or ±0.5pF, whichever is larger. $C_p < 10\text{pF}$, $Q \geq 200 + 10C_p$; $10 \leq C_p < 30\text{pF}$, $Q \geq 275 + 2.5C_p$ $C_p \geq 30\text{pF}$, $Q \geq 350$ $R \cdot C \geq 1000\text{M}\Omega$ or $50\Omega \cdot \text{F}$, whichever is smaller	测试温度: $40 \pm 2^\circ\text{C}$ 湿度: 90~95% RH 测试时间: $500 \pm 12\text{hrs}$ 在室温下放置 24 ± 2 (C0G) 或 48 ± 4 (X7R、X5R、Y5V) 小时以后测量 *高介电常数电容器的初始值测量 在 $140 \sim 150^\circ\text{C}$ 进行 1 小时的热处理后在室温下放置 48 ± 4 小时测量初始值
X7R/X5R	外观无明显可见损伤 容量变化在±12.5%以内 DF 为初始值的 2 倍以下 IR:大于 $1000\text{M}\Omega$ 或 $50\Omega \cdot \text{F}$ (取较小值) Cp change within ±12.5% DF:Not more than 2 times of initial value $R \cdot C \geq 1000\text{M}\Omega$ or $50\Omega \cdot \text{F}$, whichever is smaller	Test temperature: $40 \pm 2^\circ\text{C}$ Humidity: 90~95% RH Testing time: $500 \pm 12\text{hrs}$ Measurement to be made after being kept at room temperature for $24 \pm 2\text{hrs}$ (C0G) or $48 \pm 4\text{hrs}$ (X7R, X5R, Y5V)
Y5V	外观无明显可见损伤 容量变化在±30%以内 DF 为初始值的 1.5 倍以下 IR: 大于 $1000\text{M}\Omega$ 或 $50\Omega \cdot \text{F}$ (取较小值) No remarkable visual damage Cp change within ±30% DF:Not more than 1.5 times of initial value $R \cdot C \geq 1000\text{M}\Omega$ or $50\Omega \cdot \text{F}$, whichever is smaller	*Initial measurement for high dielectric constant type Perform a heat treatment at $140 \sim 150^\circ\text{C}$ for 1hr and let sit for $48 \pm 4\text{hrs}$ at room temperature. Perform the initial measurement.

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7.15 耐湿负荷 Damp heat with load

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	外观无明显可见损伤 容量变化在 $\pm 7.5\%$ 或 $\pm 0.75\text{pF}$ （取较大值）以内 $C_p < 30\text{pF}$, $Q \geq 100 + 10/3 * C_p$ $C_p \geq 30\text{pF}$, $Q \geq 200$ IR: 大于 $500\text{M}\Omega$ 或 $25\Omega\text{-F}$ (取较小值) No remarkable visual damage $C_p \text{ change} \leq \pm 7.5\% \text{ or } \pm 0.75\text{pF}$, whichever is larger. $C_p < 30\text{pF}$, $Q \geq 100 + 10/3 * C_p$ $C_p \geq 30\text{pF}$, $Q \geq 200$ $R * C \geq 500\text{M}\Omega \text{ or } 25\Omega\text{-F}$, whichever is smaller	测试温度: $40 \pm 2^\circ\text{C}$ 湿度: 90~95% RH 电压: 额定电压 测试时间: $500 \pm 12\text{hrs}$ 在室温下放置 24 ± 2 (C0G) 或 48 ± 4 (X7R、X5R、Y5V) 小时以后测量 *在 $40 \pm 2^\circ\text{C}$ 温度下, 将电容器加额定直流电压 1hrs. 去掉电压, 将电容器在室温下放置 $48 \pm 4\text{hrs}$ 测量初始电容值。
X7R/X5R	外观无明显可见损伤 容量变化在 $\pm 12.5\%$ 以内 DF 为初始值的 2 倍以下 IR: 大于 $500\text{M}\Omega$ 或 $25\Omega\text{-F}$ (取较小值) No remarkable visual damage $C_p \text{ change} \leq \pm 12.5\%$ DF: Not more than 2 times of initial value $R * C \geq 500\text{M}\Omega \text{ or } 25\Omega\text{-F}$, whichever is smaller	Test temperature: $40 \pm 2^\circ\text{C}$ Humidity: 90~95% RH Voltage: 100% of the rated voltage Testing time: $500 \pm 12\text{hrs}$
Y5V	外观无明显可见损伤 容量变化在 $\pm 30\%$ 以内 DF 为初始值的 1.5 倍以下 IR: 大于 $500\text{M}\Omega$ 或 $25\Omega\text{-F}$ (取较小值) No remarkable visual damage $C_p \text{ change} \leq \pm 30\%$ DF: Not more than 1.5 times of initial value $R * C \geq 500\text{M}\Omega \text{ or } 25\Omega\text{-F}$, whichever is smaller	Measurement to be made after being kept at room temperature for $24 \pm 2\text{hrs}$ (C0G) or $48 \pm 4\text{hrs}$ (X7R, X5R, Y5V) *Apply the rated DC voltage for 1 hour at $40 \pm 2^\circ\text{C}$. Remove and let sit for $48 \pm 4\text{hrs}$ at room temperature. Perform the initial measurement.

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7.16 耐久性 Life Test

类型 Dielectrics	技术要求 Specification	测试条件 Testing Condition
C0G	外观无明显可见损伤 容量变化在 $\pm 3\%$ 或 $\pm 0.3\text{pF}$ (取较大值)以内 容量在 30pF 以上, $Q \geq 350$ 容量在 10 pF 以上且小于 30 PF, $Q \geq 275 + (2.5 * C_p)$ 容量小于 10pF, $Q \geq 200 + 10 * C_p$ IR: 大于 1000M Ω 或 50 $\Omega \cdot F$ (取较小值) No remarkable visual damage Cp change $\leq \pm 3\%$ or $\pm 0.3\text{pF}$, whichever is larger. $Q \geq 350$ ($C_p \geq 30$ PF) $Q \geq 275 + (2.5 * C_p)$ (10 pF $\leq C_p < 30$ PF) $Q \geq 200 + 10 * C_p$ ($C_p < 10$ PF) $R * C \geq 1000M\Omega$ or 50 $\Omega \cdot F$, whichever is smaller	测试温度: 上限类别温度 $\pm 3^\circ\text{C}$ 电压: 2 倍额定电压 测试时间: 1000 小时 在室温下放置 24 ± 2 (C0G) 或 48 ± 4 (X7R、X5R、Y5V) 小时以后测量 *高介电常数电容器的初始值测量 在上限类别温度 $\pm 3^\circ\text{C}$, 将电容器加 2 倍额定直流电压 1 小时去掉电压, 将电容器在室温下放置 48 ± 4 hrs 测量初始电容值 Test temperature: Max. Operating Temp. $\pm 3^\circ\text{C}$ Voltage: 200% of the rated voltage Testing time: 1000 hrs
X7R/X5R	外观无明显可见损伤 容量变化在 12.5%以内 DF 为初始值的 2 倍以下 IR: 大于 1000M Ω 或 50 $\Omega \cdot F$ (取较小值) No remarkable visual damage Cp change $\leq \pm 12.5\%$ DF: Not more than 2 times of initial value $R * C \geq 1000M\Omega$ or 50 $\Omega \cdot F$, whichever is smaller	Measurement to be made after being kept at room temperature for 24 ± 2 hrs (C0G) or 48 ± 4 hrs (X7R, X5R, Y5V) *Initial measurement for high dielectric constant type Apply 200% of the rated DC voltage for one hour at the maximum operating temperature $\pm 3^\circ\text{C}$. Remove and let sit for 48 ± 4 hrs at room temperature. Perform the initial measurement
Y5V	外观无明显可见损伤 容量变化在 $\pm 30\%$ 以内 DF 为初始值的 1.5 倍以下 IR: 大于 1000M Ω 或 50 $\Omega \cdot F$ (取较小值) No remarkable visual damage Cp change $\leq \pm 30\%$ DF: Not more than 1.5 times of initial value $R * C \geq 1000M\Omega$ or 50 $\Omega \cdot F$, whichever is smaller	

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8. 产品包装 Packing

8.1 袋式散装 Bulk Packing

10000 个/袋或按客户要求

Standard packing 10Kpcs/bag; others are according to customer request.

8.2 编带式包装 Tape Packing

纸带: 10000 个/盘(0402)、4000 个/盘(0805、0603)

Paper Tape: Standard taping (8mm paper width) suitable to 0603,0805,4Kpcs/reel

To 0402, 10Kpcs/reel.

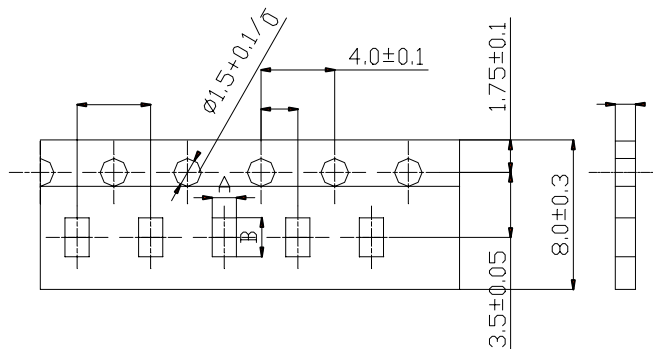
塑料带: 适合 0805、1206 规格, 厚度大于 0.95mm 的产品, 4000 个/盘或 3000 个/盘。

Plastic Tape: Suitable 0805, 1206 sizes, for chip thickness over 0.95 mm, 4Kpcs/reel

or 3Kpcs/reel are available.

8.2.1 纸带尺寸

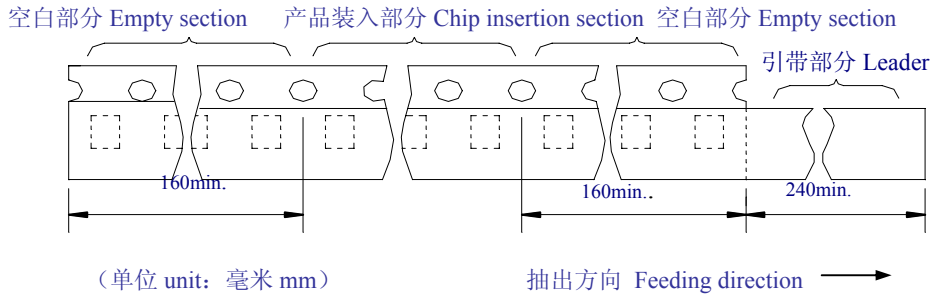
Dimensions of Packing Paper



Type	A	B	C	D	T
0402	0.65 ± 0.10	1.15 ± 0.10	2.0 ± 0.05	2.0 ± 0.05	0.8max
0603	1.05 ± 0.10	1.85 ± 0.10	4.0 ± 0.10	2.0 ± 0.10	1.1max
0805	1.55 ± 0.15	2.3 ± 0.15	4.0 ± 0.10	2.0 ± 0.10	1.1max
1206	1.95 ± 0.15	3.5 ± 0.15	4.0 ± 0.10	2.0 ± 0.10	1.1max

(单位 unit:毫米 mm)

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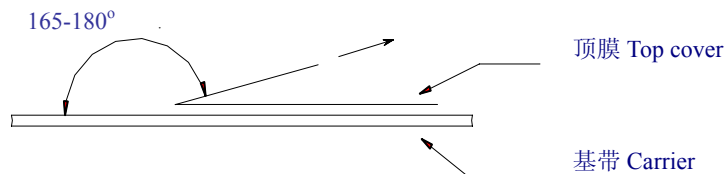


8.2.5 编带方法

Taping Method

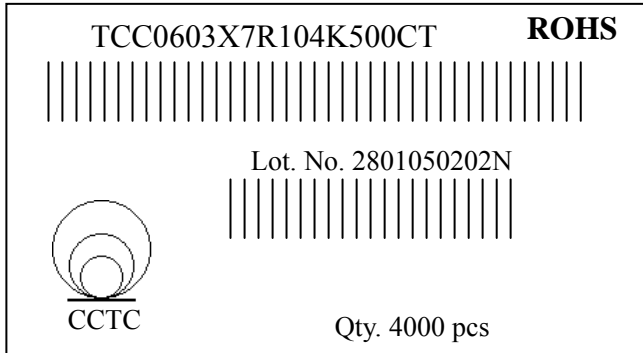
- ① 包装电容器的编带是顺时针卷绕的，由上往下的方向拉出编带时，传送孔处于编带的右侧。
- ② 在编带的前端，至少留出 5 个间距的引出带。
- ③ 在编带时，必须按下图留出引带部分或空白部分。
- ④ 在盘带的安装中的产品装错的数量每盘必须小于表示数量的 0.1% 或 1 个为限，不连续发生错误。
- ⑤ 上胶带和下胶带不应超出编带的边缘，不能挡住传送孔。
- ⑥ 传送孔的累计误差为 10 个间距：±0.3 毫米以内。
- ⑦ 上胶带的剥离力矩应在 0.1 至 0.6 牛顿以内，其方向如下图所示。

- ① Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
- ② The top tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- ③ Part of the leader and part of the empty tape shall be attached to the end of the tape as follows.
- ④ Missing capacitors number within 0.1% of the number per reel or 1pc, whichever is greater, and are not continuous.
- ⑤ The top tape and bottom tape shall not protrude beyond the edges of the tape and shall not cover sprocket holes.
- ⑥ Cumulative tolerance of sprocket holes, 10 pitches: ±0.3mm.
- ⑦ Peeling off force: 0.1 to 0.6N in the direction shown down.



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8.2.6 产品标签 Reel Label



标签内容 The Contents of Label

- (1) TCC 0603 X7R 104 K 500 C T
 ① ② ③ ④ ⑤ ⑥ ⑦ ⑧

①陶瓷电容器代号 Code of Ceramic Capacitor

②尺寸 chip size,③温度特性 dielectrics,④容量 capacitance,⑤容量容差 tolerance,
 ⑥额定电压 rated voltage,⑦厚度 thickness, ⑧包装 packing

(2) 产品批号 Lot. No.:2801050202N

(3) 数量 Qty: 4000pcs

(4) ROHS:GREEN PARTS 绿色物料

8.2.7.外包装 Package

8.2.7.1 包装箱 Carton

8.2.7.1.1 包装箱尺寸 Carton Size

L	W	H
40cm	36cm	20cm

8.2.7.1.2 数量: 500Kpcs /箱 The Quantity: 200Kpcs /one carton

1 内包装盒=20,000PCS 1 INNER BOX=20,000PCS

1 包装箱 =20,000PCS × 10 包装盒=200,000PCS 1 CARTON=20,000PCS × 10BOX=200,000PCS

200Kpcs /箱 The Quantity: 200Kpcs /one carton

1 内包装盒=20,000PCS 1 INNER BOX=20,000PCS

1 包装箱 =20,000PCS × 10 包装盒=200,000PCS 1 CARTON=20,000PCS × 10BOX=200,000PCS

RoHS 标识(根据客户要求张贴) according to customer request

8.2.7.2 内包装盒 Inner Box

8.2.7.2.1 包装盒尺寸 Size

L	W	H
18.5cm	6.5cm	19cm

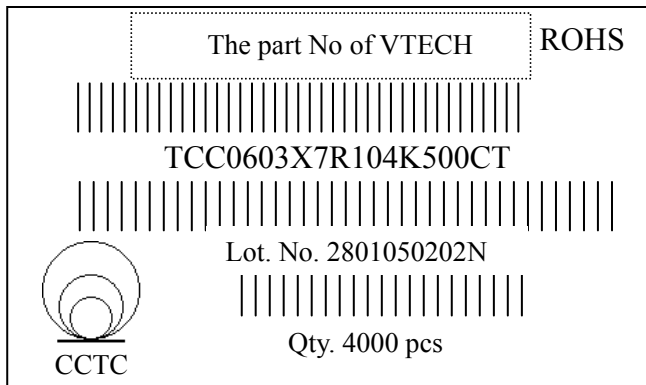
8.2.7.2.2 数量: 20Kpcs /盒

1 盘=4000PCS 1 REEL=4,000PCS

1 包装盒=4,000PCS × 5 盘 =20,000PCS 1 INNER BOX=4,000PCS × 5 REEL =20,000PCS

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8.2.7.2.3 内包装盒标签 The Label in Inner Box



9.产品禁用物质检验结果 About RoHS

所有产品均符合 ROHS 指令要求（附产品 SGS 测试报告）

All products accord with RoHS(attached SGS test report)

类别 Sort	检测机构 Test organization	检测报告编号 Report No.	检测日期 Test Date	检测结论 Test Result	有效期限 Expiry
C0G 片式陶瓷电容器 C0G MLCC	SGS	CANEC1000031503	2010-01-12	OK	2011-01-12
X7R 片式陶瓷电容器 X7R MLCC	SGS	CANEC1000031501	2010-01-12	OK	2011-01-12
X5R 片式陶瓷电容器 X5R MLCC	SGS	CANEC1000031502	2010-01-12	OK	2011-01-12
Y5V 片式陶瓷电容器 Y5V MLCC	SGS	CANEC1000031504	2010-01-12	OK	2011-01-12

必要时可以在产品标签标示 RoHS 标志

Mark RoHS on label of products if necessary



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10.MLCC 使用注意事项 **Precautions on the use of MLCC**

10.1 电路板设计 PCB Design

10.1.1 电路板图案设计 Design of Land-patterns

下面图和表格给出了部分推荐的设计图案，可以防止安装时焊锡量过多。

同时也给出了不正确的图案。

The following diagrams and tables show some examples recommended patterns to prevent excessive solder amounts (larger fillets which above the component end terminations)

Examples of improper pattern designs are also shown.

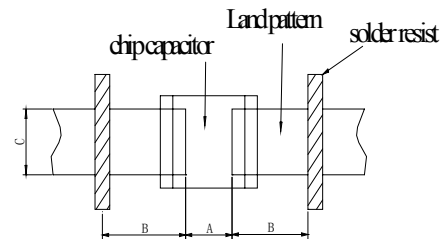
电路板设计推荐图案尺寸：

Recommended land dimensions for a typical chip capacitor land patterns for PCBs

波峰焊接时推荐设计的尺寸 (单位: mm):

Recommended land dimensions for wave-soldering (unit: mm)

规格 SIZE	0603	0805	1206	
尺寸	L	1.6	2.0	3.2
	W	0.8	1.25	1.6
A	0.8~1.0	1.0~1.4	1.8~2.5	
B	0.5~0.8	0.8~1.5	0.8~1.7	
C	0.6~0.8	0.9~1.2	1.2~1.6	



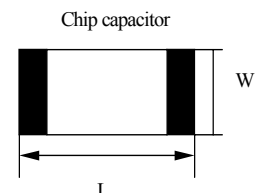
再流焊接时推荐设计的尺寸 (单位: mm)

Recommended land dimensions for reflow-soldering (unit: mm)

再流焊接时推荐设计的尺寸 (单位: mm)

Recommended land dimensions for reflow-soldering (unit: mm)

规格 SIZE	0402	0603	0805	1206	
尺寸	L	1.0	1.6	2.0	3.2
	W	0.5	0.8	1.25	1.6
A	0.45~0.35	0.6~0.8	0.8~1.2	1.8~2.5	
B	0.40~0.50	0.6~0.8	0.8~1.2	1.0~1.5	
C	0.45~0.55	0.60~0.80	0.9~0.1.6	1.2~2.0	



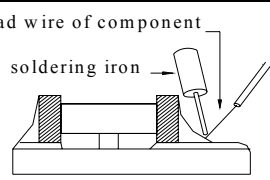
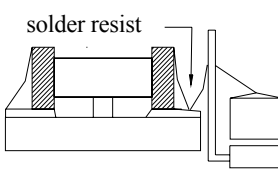
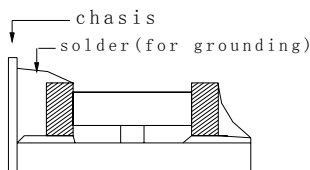
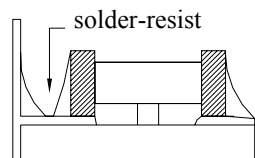
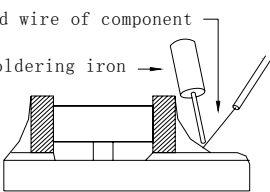
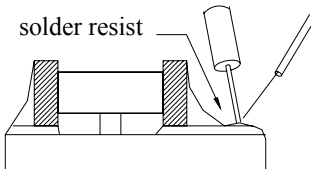
过量的焊锡会影响产品抵抗机械应力的能力，因此在设计图案时应引起注意。

Excess solder can affect the ability of chips to withstand mechanical stresses. Therefore, please take proper precautions when designing land-patterns.

在应用中一些焊接好与坏的情况：

Examples of good and bad solder application

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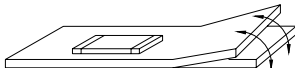
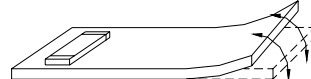
项目 Item	不推荐结构 Not recommended	推荐结构 Recommended
片状元件和带引线的元件的混合焊接 Mixed mounting of SMD and leaded component		
靠近底座的焊接 Component placement close to the chassis		
在片状元件附近带引线元件的焊接 Hand-soldering of leaded components near mounted components		

10.1.2 图案结构

Pattern configurations

下面是电容器安装好与坏的样子。选择贴装位置，应尽可能减小电路板在弯曲时受到的机械应力。

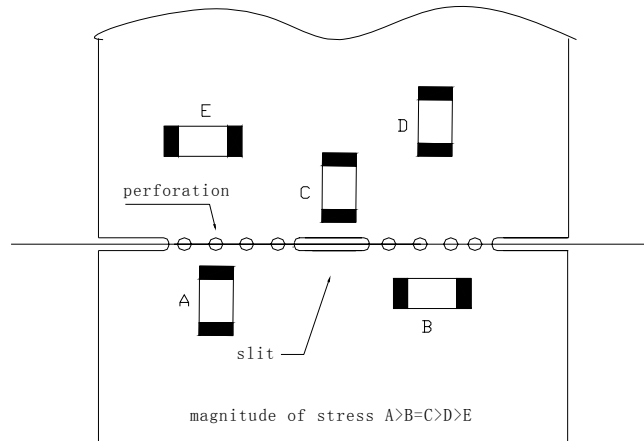
The following are examples of good and bad capacitor layout, SMD capacitors should be located to minimize any possible mechanical stresses from board warp or deflection..

	不推荐结构 Not recommended	推荐结构 Recommended
电路板弯曲 Deflection of the board		

对于电路板分拨的电容器，在分拨时受到的机械应力大小与电容器的安装有关。下面推荐了一些好的设计。

To layout the capacitors for the breakaway PC board, it should be noted that the amount of mechanical stresses given depending on capacitor layout. The example below shows recommendations for better design.

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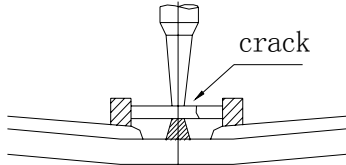
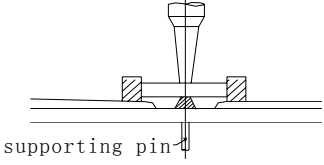
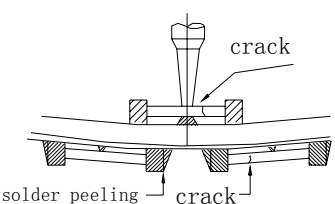
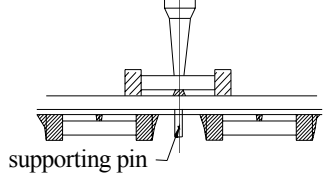
在沿着分拨线分拨电路板时，对产品施加的机械应力与使用的方法关系很大。分折电路板时片状元件受到的疲劳按照如下顺序增大：分折、剪切、V型槽、穿孔。因此，贴装时应该考虑电路板的分拨过程。

When breaking PC boards along their perforations, the amount of mechanical stress on the capacitors can vary according to the method used. The following methods are listed in order from least stressful to most stressful: push-back, silt, -grooving, and perforation. Thus, any ideal SMD capacitor layout must also consider the PCB splitting procedure.

10.2 自动贴装注意事项 Considerations for automatic placement

贴装机的调整 Adjustment of mounting machine

- ①. 产品在电路板贴装时，不应该受到过大的冲击。
- ②. 必须定期对吸头和定位爪进行检查、维修和更换
- ①. Excessive impact load should not be imposed on the capacitors when mounting the PC boards.
- ②. The maintenance and inspection of the mounters should be conducted periodically.

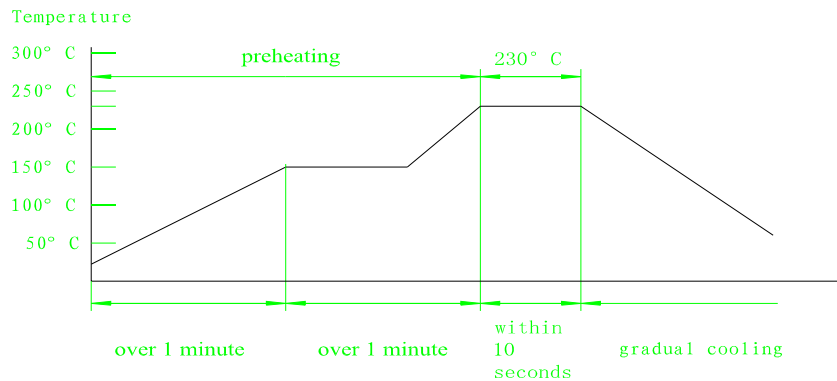
	不推荐结构 Not recommended	推荐结构 Recommended
单面贴装 Single-sided mounting		
双面贴装 Double-sided mounting		

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10.3 推荐焊接曲线 Recommended soldering profile

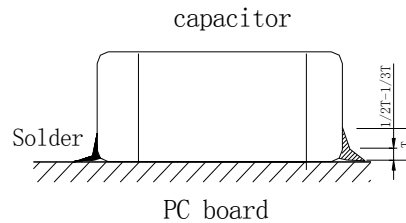
10.3.1 锡铅焊接曲线 Recommended Sn&Pb soldering profile

再流焊 Reflow soldering



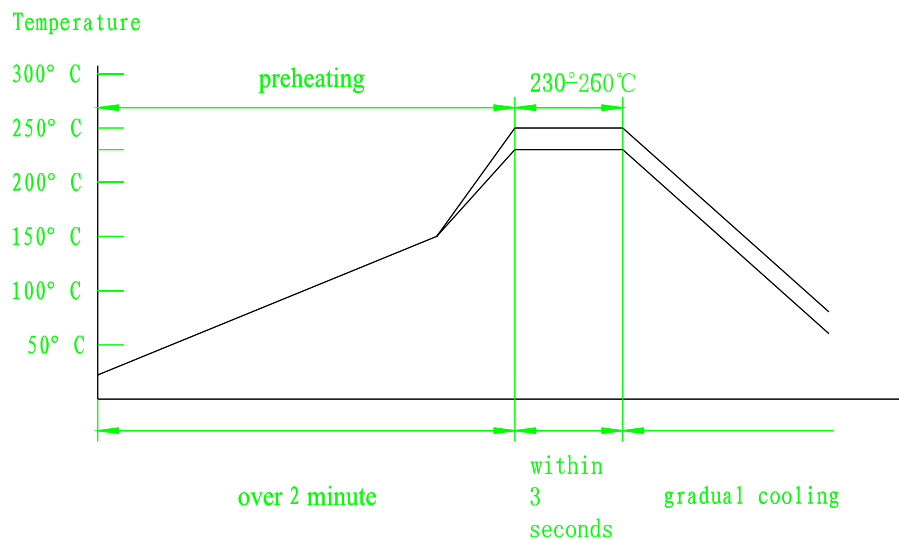
注意 Caution

- ①. 理想状况的焊锡高度为电容器厚度的 1/2 ~1/3，如下图所示：
- ①.The ideal condition is to have solder mass (fillet) controlled to 1/2 to 1/3 of the thickness of the capacitor, as shown below:



- ②. 过长的焊接时间会影响端头的可焊性，焊接时间尽可能保持与推荐时间一致。
- ②. Because excessive dwell times can detrimentally affect solderability, soldering duration should be kept as close to recommended times as possible.

波峰焊 Wave solder profile

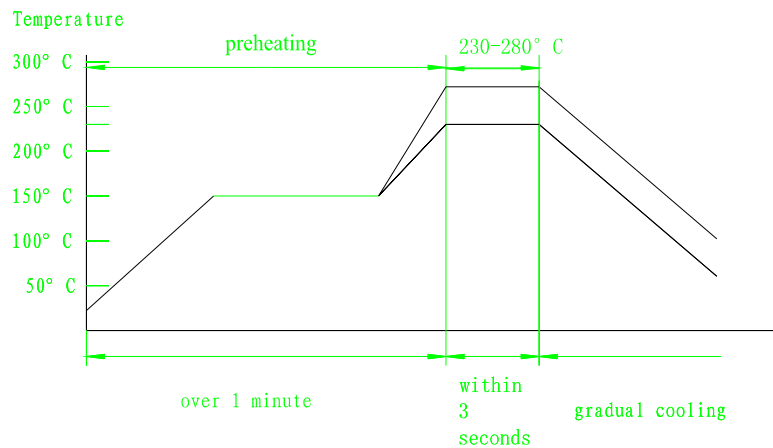


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注意 Caution

- ①. 确保电容器充分预热。
- ②. 产品预热和焊接温度差不超过 100~130℃。
- ③. 焊接后尽可能慢速冷却。
- ①. Make sure the capacitors are preheated sufficiently.
- ②. The temperature difference between the capacitor and melted solder should not be greater than 100 to 130℃.
- ③. Cooling after soldering should be gradual as possible.

手工焊接 Hand soldering

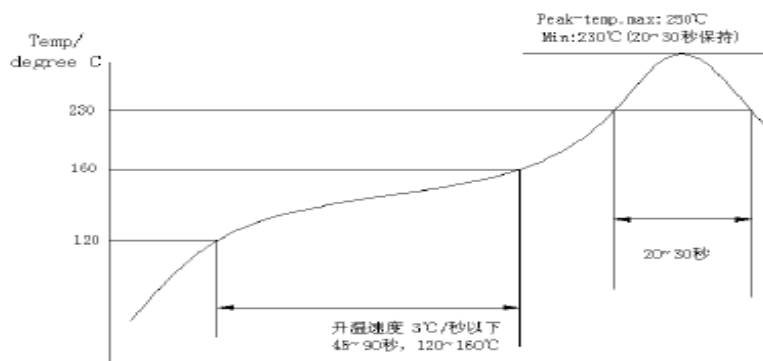


注意 Caution

- ①. 用尖端最大直径 1.0mm 功率 20W 的焊接烙铁。
- ②. 焊接烙铁不要直接接触产品。
- ①. Use a 20w soldering iron with a maximum tip diameter of 1.0mm.
- ②. The soldering iron should not directly touch the capacitor.

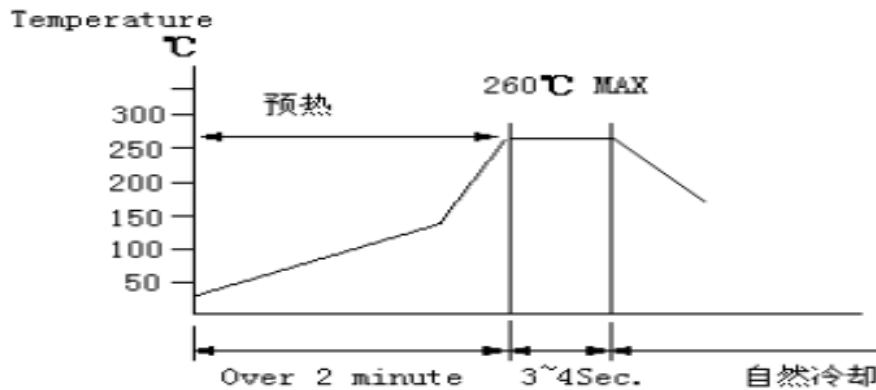
10.3.2 无铅焊接曲线 Recommended Pb-Free soldering profile

再流焊接 Reflow soldering



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波峰焊接 Wave solder profile



10.4 分拨电路板 Handling

Breakaway PC boards (splitting along perforations)

(1).在电容器或其它贴装后，必须注意因电路板弯曲或变形带来的应力。

(2).分拨电路板时必须使用专用的夹具，不可以用手拨断。

(1).When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of deflection or twisting to the board.

(2).Board separation should not be done manually, but by using the appropriate devices.

10.5 保存 Storage

(1).在下列环境中保存产品：温度 5~40°C；湿度 ≤70% RH

(2).产品自生产之日保存期为一年，产品使用之前请勿拆开编带。

(3).编带拆开后，产品应在三个月内使用。

(4).高介电常数电容器 (X7R,X5R,Y5V) 的容值随时间会逐渐减小，所以在电路设计时应充分考虑这一现象。容值减小的电容器在 150°C 热处理 1 小时后容值会恢复到初试值。

(1). Keep the storage environment conditions as following:

Temperature: 5~40°C

Humidity: ≤70% RH

(2). Don't open the tape until the parts are to be used, and store them within one year since the date printed on the reel.

(3). Use the chips within 3 months after the tape is opened.

(4). The capacitance value of high dielectric constant capacitors (X7R,X5R,Y5V) will gradually decrease with the passage of time, so this should be taken into consideration in the circuit design. If such a capacitance reduction occurs, a heat treatment of 150°C for 1 hour will return the capacitance to its initial level.

